

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims

1. (Currently amended) A device for checking and rotating electronic components, in particular flip chips, with a pivoting part (14) attached to a pivotal point (17) for rotating the electronic components, on the exterior of which pivoting part (14) a first pickup element (19) is fixed for taking up a single electronic component from a substrate (14) and keeping hold of it during a rotational movement (15, 16; 15a) of the pivoting part (14), characterized in that a second pickup element (20) is arranged externally on the part (14) opposite the first pickup element (19) in relation to the pivotal point (17) in such a way that in each case one pickup element (19, 20) is facing the substrate (11) for each rotation (15, 16) of the part (14) through 180°, and that in the pivoting part (14) a through opening (28) is arranged between the pickup elements (19, 20) in such a way that the through opening (28) is facing the substrate (11) for a rotation (15, 16) of the pivoting part (14) through 90° or 270°.
2. (Currently amended) Device according to Claim 1, characterized in that the first pickup element (19) is attached on a first projection (18a) and the second pickup element (20) on a second projection (18b) of the part (14).

3. (Currently amended) Device according to Claim 2, characterized in that the through opening ~~(28)~~ is developed between the projections ~~(18a, 18b)~~ as a through channel ~~(28)~~ open on one long side.
4. (Currently amended) Device according to claim 1 ~~one of the preceding claims~~, characterized in that on a side of the pivoting part ~~(14)~~ facing the substrate ~~(11)~~ a first optical facility ~~(23)~~ is arranged for optical checking of surfaces and correct positions of the electronic components arranged on the substrate ~~(11)~~ before being picked up.
5. (Currently amended) Device according to Claim 4, characterized in that the through opening ~~(28)~~ is formed in such a way that it permits an optical connection between the first optical facility ~~(23)~~ and an electronic component arranged on the substrate (11) during a rotational movement ~~(15, 16)~~ of the pivoting part ~~(14)~~.
6. (Currently amended) Device according to claim 1 ~~one of the preceding claims~~, characterized by a second optical facility ~~(25)~~ for checking a correct position of the rotated and deposited electronic component.
7. (Currently amended) Method for checking and rotating electronic components, in particular flip chips, which are picked up individually from a sandwich of electronic components arranged on a substrate ~~(11)~~, by means of a first pickup element ~~(19)~~ arranged on a pivoting part, ~~(14)~~ and are deposited in a rotated position, the pivoting

part (14) being placeable between the substrate (11) and a first optical facility (23) for checking the surface and the correct position of a single component arranged on the substrate (11), characterized in that during a 180° rotation (15, 16) of the pivoting part (14) a pickup by the first pickup element (19) of a single electronic component arranged on the substrate (11), a check of a surface and the correct position of a further electronic component arranged on the substrate (11), by means of the optical facility (23) and a through opening (28) arranged in the pivoting part (14), a depositing of the electronic component held by the first pickup element (19) on a placing facility (21) after a 180° rotation (15, 16) of the pivoting part (14) and at the same time a further pickup of the further individual electronic component arranged on the substrate (11), by a second pickup element (20) arranged externally opposite the first pickup element (19) on the pivoting part (14), are executed.

8. (Currently amended) Method according to Claim 7, characterized in that after the 180° rotation (15) a 180° rotation (16) going in the ~~other~~ opposite direction is executed.
9. (Currently amended) Method according to Claim 7 ~~or 8~~, characterized in that by means of a second optical facility (25), a correct position of the turned and deposited component is checked and adjusted during or after its transport.
10. (Currently amended) Method according to claim 7 ~~one of the claims 7—9~~, characterized in that the first optical facility (23) is activated with a predefinable time

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delay (~~37, 38~~) after a rotation of the through opening (~~28~~) into an optical connection line (~~23a~~) between the first optical facility (~~23~~) and the electronic component still arranged on the substrate (~~11~~).